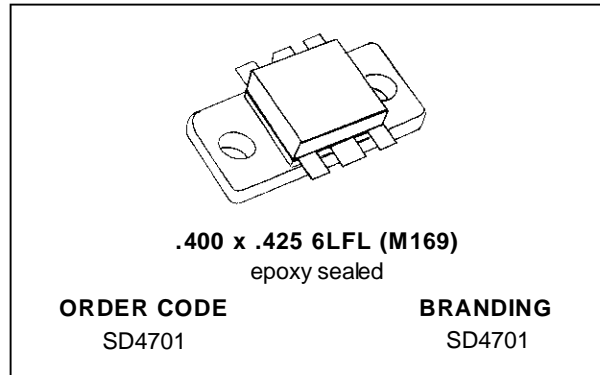




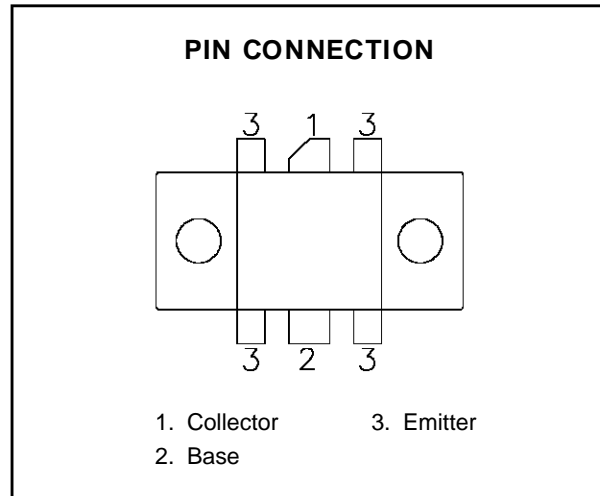
SD4701

**RF & MICROWAVE TRANSISTORS
CELLULAR BASE STATION APPLICATIONS**

- DESIGNED FOR CLASS AB LINEAR OPERATION
- COMMON EMITTER
- INTERNAL INPUT/OUTPUT MATCHING
- 26 VOLT, 960 MHz PERFORMANCE:
 - P_{OUT} = 45 W MIN.
 - GAIN = 8.5 dB MIN.
 - COLLECTOR EFFICIENCY 50% MIN.
- INHERENT RUGGEDNESS:
 - LOAD MISMATCH TOLERANCE OF 5:1 MIN. VSWR
 - 3 dB OVERDRIVE CAPABILITY



DESCRIPTION



ABSOLUTE MAXIMUM RATINGS (T_{case} = 25°C)

Symbol	Parameter	Value	Unit
V _{CB0}	Collector-Base Voltage	60	V
V _{CEO}	Collector-Emitter Voltage	30	V
V _{CER}	Collector-Emitter Voltage	40	V
V _{EBO}	Emitter-Base Voltage	3.5	V
I _c	Device Current	10	A
P _{DISS}	Power Dissipation	145	W
T _J	Junction Temperature	+200	°C
T _{STG}	Storage Temperature	- 65 to +150	°C

THERMAL DATA

R _{TH(j-c)}	Junction-Case Thermal Resistance	1.2	°C/W
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ELECTRICAL SPECIFICATIONS (T_{case} = 25°C)

STATIC

Symbol	Test Conditions		Value			Unit
			Min.	Typ.	Max.	
BV _{CBO}	I _C = 60 mA	I _E = 0 mA	60	—	—	V
BV _{CEO}	I _C = 60 mA	I _B = 0 mA	30	—	—	V
BV _{CER}	I _C = 60 mA	R _{BE} = 75 Ω	40	—	—	V
BV _{EBO}	I _E = 10 mA	I _C = 0 mA	3.5	—	—	V
I _{CER}	V _{CE} = 26 V	R _{BE} = 75 Ω	—	—	15	mA
h _{FE}	V _{CE} = 10 V	I _C = 1 A	15	—	100	—

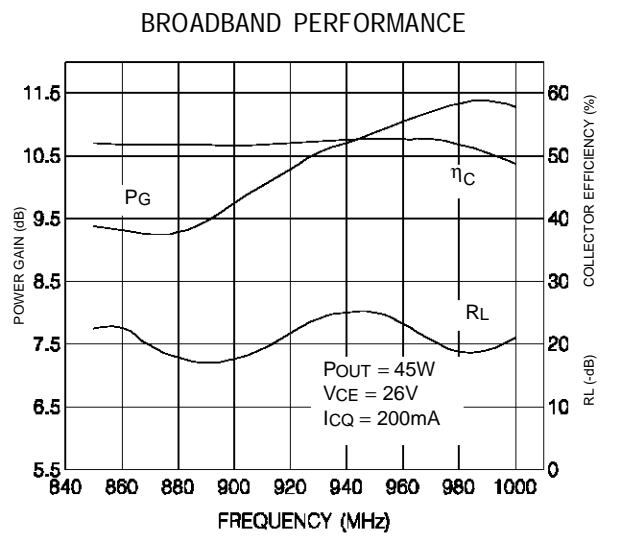
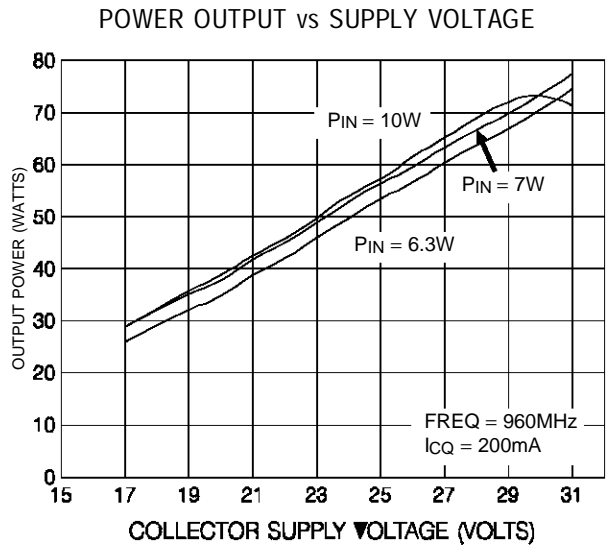
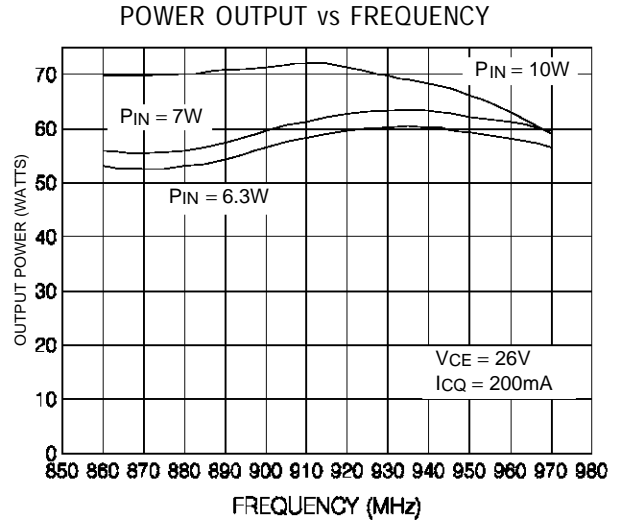
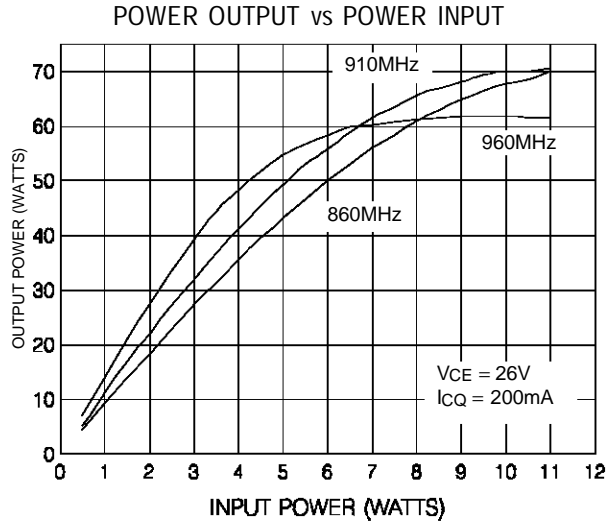
DYNAMIC

Symbol	Test Conditions		Value			Unit
			Min.	Typ.	Max.	
C _{OB}	f = 1 MHz	V _{CB} = 26 V For Information Only - This Device is Collector Matched	—	55	—	pF
P _{IN}	f = 960 MHz	V _{CE} = 26 V I _{CQ} = 200 mA P _{OUT} = 45 W	—	5	6.3	W
P _{OUT}	f = 960 MHz	V _{CE} = 26 V I _{CQ} = 200 mA P _{IN} = 6.3 W	45	55	—	W
G _P	f = 960 MHz	V _{CE} = 26 V I _{CQ} = 200 mA P _{OUT} = 45 W	8.5	9.5	—	dB
η _c	f = 960 MHz	V _{CE} = 26 V I _{CQ} = 200 mA P _{OUT} = 45 W	50	55	—	%
Load Mismatch	f = 960 MHz	V _{CE} = 26 V I _{CQ} = 200 mA P _{OUT} = 45 W VSWR = 5:1 MIN. @ All Phase Angles	No Degradation in Device Performance			
OVD	f = 960 MHz	V _{CE} = 26 V I _{CQ} = 200 mA Set P _{OUT} = 45 W; Increase P _{IN} 3dB	No Degradation in Device Performance			
*IMD ₃	V _{CE} = 26 V I _{CQ} = 200 mA	P _{OUT} = 46.5 dBm (45.0W) PEP	—	-32	—	dB ^T **

*Note: f₁ = 900.00MHz @ 40.5dBm
f₂ = 900.01MHz @ 40.5dBm

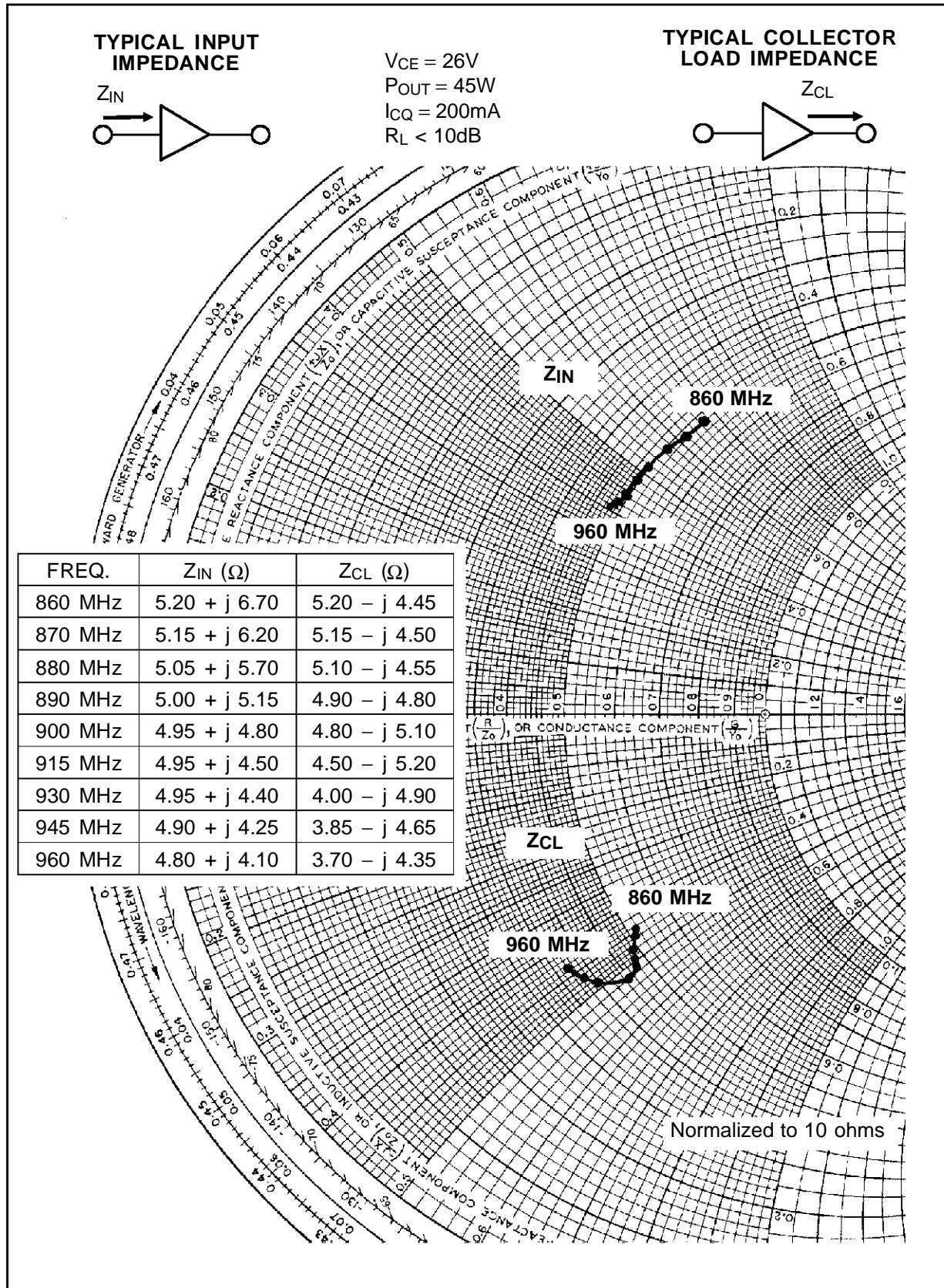
** dB^T, in dB, referenced to tone level

TYPICAL PERFORMANCE



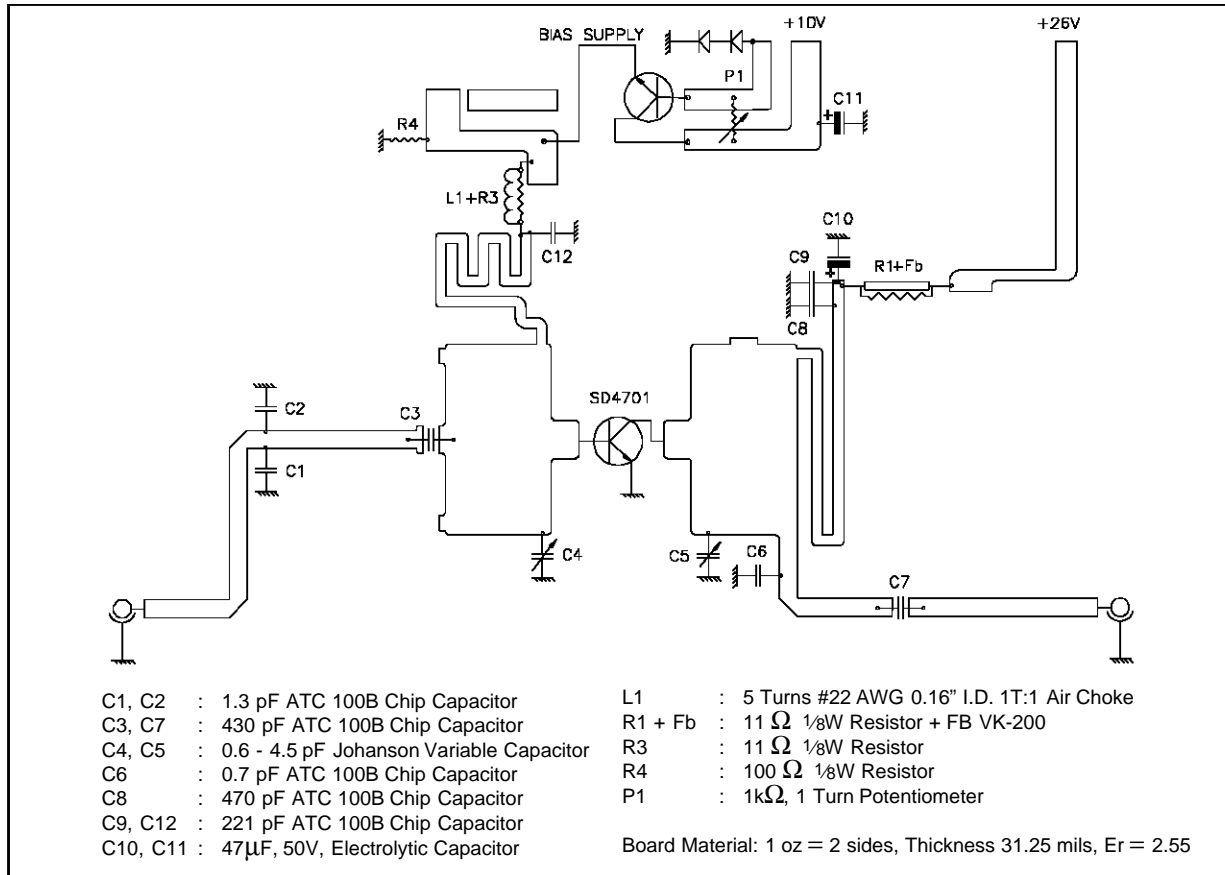
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IMPEDANCE DATA

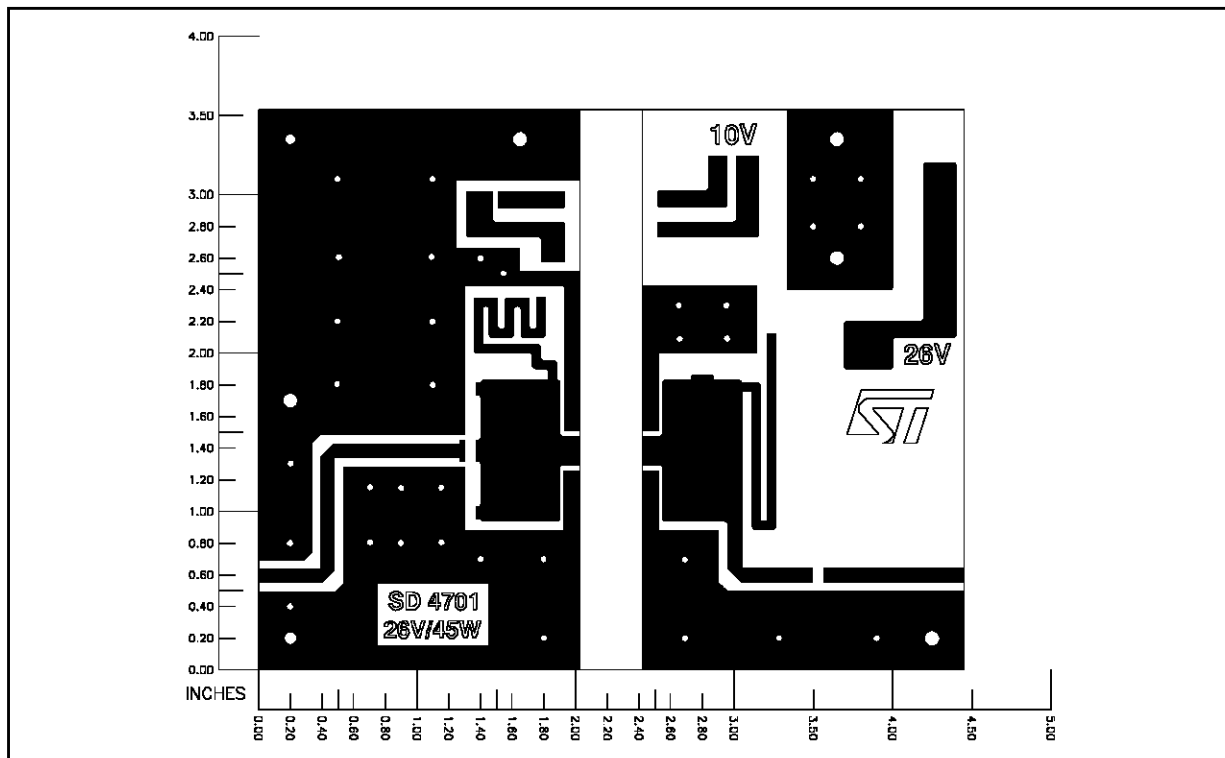


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TEST CIRCUIT



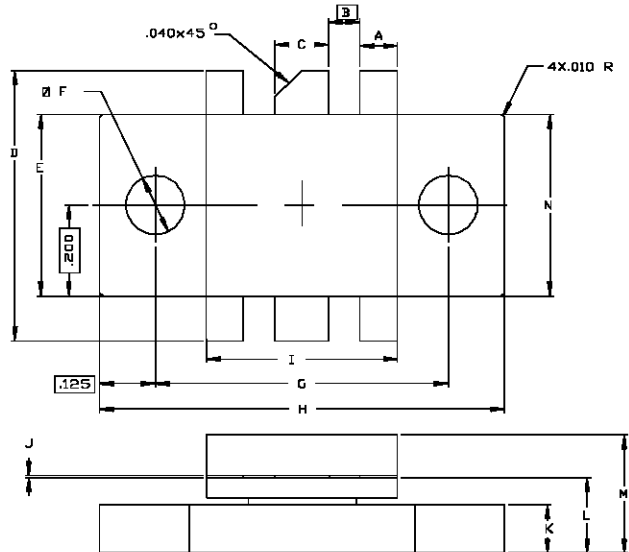
TEST CIRCUIT PHOTOMASTER



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PACKAGE MECHANICAL DATA

Ref.: Dwg. No.12-0169



SGS-THOMSON MICROELECTRONICS		CONT'D			
	MINIMUM Inches/mm	MAXIMUM Inches/mm		MINIMUM Inches/mm	MAXIMUM Inches/mm
A	.078/1,98	.088/2,24	K	.105/2,67	.115/2,92
B	.120/3,05		L	.159/4,04	.175/4,45
C	.115/2,92	.125/3,18	M		.280/7,11
D	.580/14,73	.620/15,75	N	.395/10,03	.408/10,36
E	.395/10,03	.405/10,29			
F	.125/3,18				
G	.720/18,29	.730/18,54			
H	.970/24,64	.980/24,89			
I	.420/10,67	.430/10,92			
J	.002/0,05	.007/0,18			

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